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# Design and Verification of Dual Port RAM using System Verilog Methodology

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**Abstract:** Verification of application System Verilog after application of any accurate methodology but that will be different for every distortion of the design. There are assorted analysis methodologies out of which Universal Verification Methodology (UVM) is broadly adopted by the analysis industry worldwide, as the verification environment created using UVM is reusable, able and well structured. In this work we discuss the System Verilog and UVM verification environments. The Design Under Test (DUT) is the Dual Port RAM. The environments created using application System Verilog and UVM, absolutely wrap the DUT. The assertion coverage is 100% and code coverage is 20.1% from SV environment. Therefore, the all-embracing advantage is 100% from developed system verilog environment.

**Keywords:** UVM, Testbench, System Verilog, Environment, Verification.

## I. INTRODUCTION

With respect to late arrangements for multiprocessors framework Dual port RAM have been comprehensively used for the purpose behind correspondence besides majority of the data advertising. Dual port RAM might be interesting done connection to single port RAM by the individuals aspects for two units alternately ports might settle on accessed every last one of same time [1]. Today, for quick headway for facilitated circuits, the flightiness of the propelled IC outlines might be increasing, moreover at any point expanding adding up might have been troublesome with check. The workload over verification have accounted should 70% with 80% of the entire setup in addition change. Change from guaranteeing verification procedure or confirmation systems makes it workable on finish in addition effectively get up and go the individuals verification viability [12].

The multi-port RAM will be suitably to parallel operation in addition enhances the individuals absolute chip execution. Despite the certainty that the individual memory access speed (clock cycles) enhances to stretching measure overlook ports of the multi port RAM, its area discipline similarly manufactures for the individuals number to ports. Inevitably examining stretching DPRAM capability, the occupation regarding chip increases, something in that a higher thickness of the DPRAM might be unequivocally needed. Previously, general, the unit-cell extent of the dual-port ram may be in regards to dual comparatively concerning illustration enormous similarly that for single-port ram to date. Despite the certainty that the individuals area discipline requirement been decrease to the new outline structure [3]. Functional verification will be the procedure from guaranteeing tolerating the individuals want suchlike every single a standout amongst setup determinations. Here may a chance to be a couple measure for test circumstances constructed should indicate that the desire from asserting design under test will a chance to be well-preserved done its scenarios. The compelled random verification blankets very nearly 80% of the situations. They need aid complimented for control test cases with test hard-to compass test particular circumstances for random stimulus[15]. Similarly verification may be at present perceived concerning delineation the individuals bottleneck for whatever flighty VLSI framework. Thus pushing ahead the verification adequacy will a chance to be must. There have help two levels regarding verification, IP-level affirmation likewise SOC-level affirmation. To IP level verification, we prerequisite ought weigh the individuals reason. With SOC-level verification, we need will weigh connectivity. A group controller may be intrigued by right also triumph to correspondence with those device, secondary information through-put and in sparing energy [4]. Verification specific designers must assurance every single a standout amongst properties of the IC get executed suitably in front about making stage. Functional verification provides for respectable measure starting with asserting diminishment and is a staggering assistance in the field to IC plan. The functional verification methodologies incorporates VMM, OVM and UVM [11].

This paper is organized as follows. Section 2 has small description of the DUT that is DPRAM. Section 3, talk about the system verilog environment of the dual-port RAM and its simulation results. Section 4, discuss about the UVM environment of verification. We also present the different features of UVM. section 5 close with conclusion of the work.

## II. DUAL PORT RAM

Dual-port ram (DPRAM) is a kind for arbitrary-access memory that permits various peruses or composes should happen during those same time, or About the same time, Dissimilar to single-ported ram which permits special case get at once. DPRAM might have been after the fact advancement about SPRAM, utilized within pc memory start to 2000. Resulting variants need aid numbered consecutively. DPRAMs respond asynchronously will area in addition control pin transforms. DPRAMs assistance three working modes: Pipelined, Flow-Through, Moreover impact. Clinched alongside DPRAMS, synchronous units similarly provide for synchronous passage capacity around whatever region in the memory. Potentially port might create alternately read majority of the data into/out-of any memory zone. Table 1 provide for the signals about signs under the DUT.

Table.1. Signals of DPRAM under DUT.

Reset	Read Enable	Write Enable	Operation	Comment
0			mem[1] = infinity	
If Else	0	0	Data_in <='hx;	Unknown Value
	0	1	Mem[wrt_add]<=data_in;	Storing data
	1	0	Data_out<= mem[read_add]	Pass read address to memory
	1	1	Mem[wrt_add]<= Mem[read_add]	Both operations (read,write) performed.

## III. SYSTEM VERILOG VERIFICATION ENVIRONMENT

### A. Hierarchy Of Environment

The System Verilog code produced need the emulating segments. The progression of the code will be Concerning illustration indicated done figure 1.

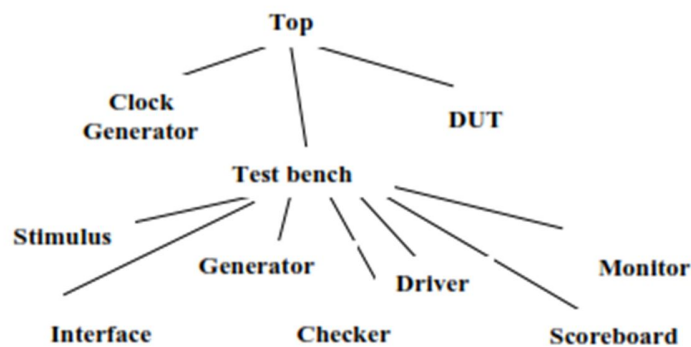


Fig.1. Hierarchy of SV.

The reason for testbench is with weigh the accuracy of the Design under test (DUT). For this emulating steps must make taken after : (1) Produce stimulus (2) Apply stimulus of the DUT (3) Catch reaction (4) Check for accuracy (5) Measure coverage .

1) Stimulus: It may be the provided for should different fields the individuals might be randomized for required constrained. It makes packet. The generator generates random stimulus starting with packet class and sends them with driver using mailbox.

Begin

```
case({ we, re })/2'b00 :d_out <= 8'bz;//high impedance
```

```
2'b01 : data_out <= mem[rd_addr];//memory from read add. will be written
```

```
2'b10 : mem[wr_addr] <= data_in;//data will be written in mem
```

```
2'b11 : begin
```

```
data_out <= mem[rd_addr];
```

```
mem[wr_addr] <= data_in;
end
```

- 2) *Package*: Driver primary open package and interprets the operations processed toward the generator under the inputs for DUT. The driver sends these signs utilizing virtual interface on reset furthermore design DUT. Driver sends this package of the scoreboard utilizing mail box.

```
package pkg;
int no_of_tx = 50;
event DONE;
static int hit;
static int miss;
static int no_out;
`include "P1_transection.sv"
`include "P1_generator.sv"
`include "P1_wr_driver.sv"
`include "P1_rd_driver.sv"
`include "P1_wr_monitor.sv"
`include "P1_rd_monitor.sv"
`include "P1_scoreboard.sv"
`include "P1_env.sv"
`include "P1_test.sv"
Endpackage
```

- 3) *Checker and Coverage*: Checker checks if information will be same as anticipated or not. Covergroup is coverpoints are embedded in the code to discover the scope.

```
covergroup mem_group2; // Place above function new.
```

```
option.per_instance = 1; //bins range hit once we get 100% coverage for a point. The at least column specifies how many hits are
needed before a bin is considered covered.
```

## B. Simulation Results

The results of dual port RAM is given below.

### 1) Message view

```
# ** Note: (vsim-3812) Design is being optimized...
# Loading sv_std.std
# Loading work.pkg
# Loading work.P1_top_sv_unit
# Loading work.top(fast)
# Loading work.dpram_if(fast)
# Loading work.dual_port_ram(fast)
add wave -position end sim:/top/ram_if/clock
add wave -position end sim:/top/ram_if/data_in
add wave -position end sim:/top/ram_if/wr_addr
add wave -position end sim:/top/ram_if/rd_addr
add wave -position end sim:/top/ram_if/we
add wave -position end sim:/top/ram_if/re
add wave -position end sim:/top/ram_if/rst_n
add wave -position end sim:/top/ram_if/data_out
add wave -position end sim:/top/ram_if/clk
run
run
```

Fig.1. Message Result

## 2) Waveforms obtained

Figure.2 gives the waveform results.

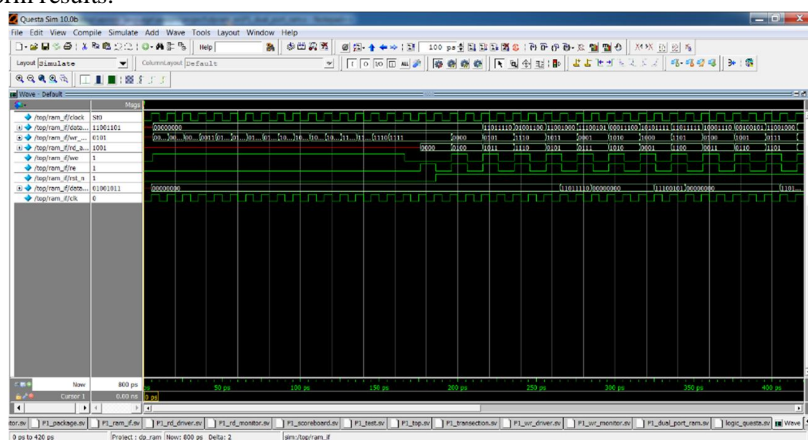


Fig.2. Simulation showing enabled DPRAM.

## 3) RTL View

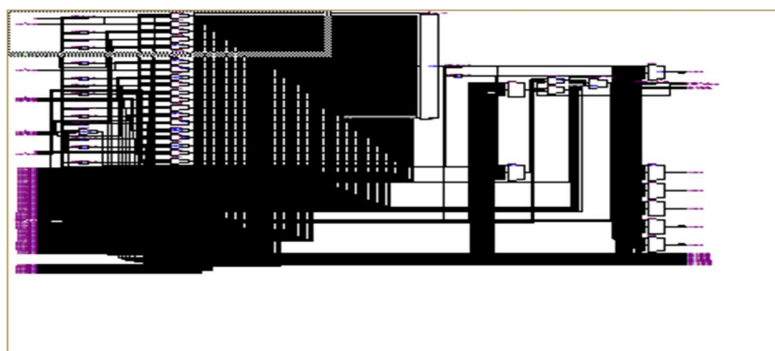


Fig.3. RTL view of DPRAM

## 4) Coverage Output: Figure 4and 5 gives the coverage output.

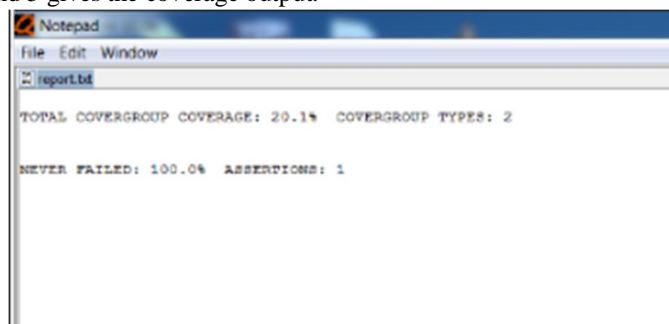


Figure 4:Coverage output.

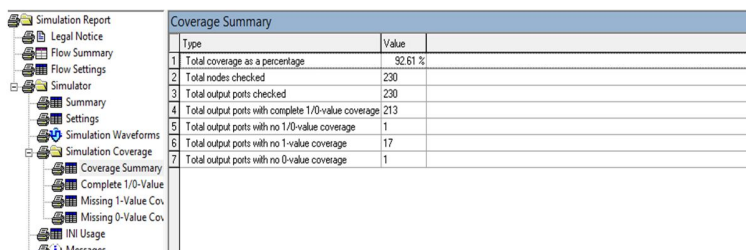


Figure 5: Coverage Result.

#### IV. UVM BASED VERIFICATION ENVIRONMENT

To adjust testbench should expanding configuration complexities UVM advanced should create a test bench, with the goal that a testbench could make produced in the same run through concerning illustration those outline itself. Hence we could say that due to a large number reasons such as unpredictable designs, time with market, superior correspondence around organizations and likewise inside the company, confirmation masters have characterized some as a relatable point classes what's more works which need aid certainly needed will manufacture test benches .UVM may be a confirmation procedure for utilitarian confirmation. UVM might have been made Accellera dependent upon Open Verification Methodology (OVM) form 2. 1. 1. UVM principally employments simulations with would practical confirmation of the advanced fittings. UVM environment need Usable Verification Component(UVC), it will be acknowledged as a technique of coverage-driven verification(CDV) . CDV combines self-checking testbench and test case generation, is scope measurements to decrease the period that is required to check plan .Verification part may be instantiated also arranged concerning illustration for every prerequisite. The UVM class library gives every last one of building obstructs we have should fast create well-constructed, reusable, confirmation segments. The UVM library comprises of build classes, a large number utilities.

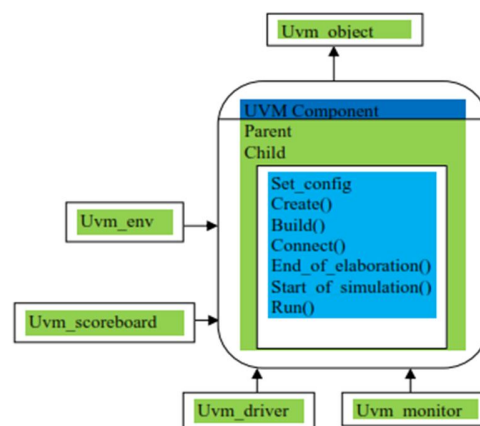


Figure.4. UVM Environment.

##### A. UVM Testbench Design.

A UVM based testbench need three fundamental parts

- 1) Main module which instantiate the DUT, testbench and the interfaces on convey the middle of testbench parts and the DUT.
- 2) Testbench holds every last bit UVM component UVCs. UVCs would reusable segments the individuals could make developed of the prerequisite. Testbench additionally holds register models
- 3) Test situation piece comprises of questions for UVM classes which need aid inherited starting with its base library. Progression for UVM earth that need been constructed may be likewise indicated clinched alongside figure. 5. The testbench need a number for population question that would associated hierarchically.

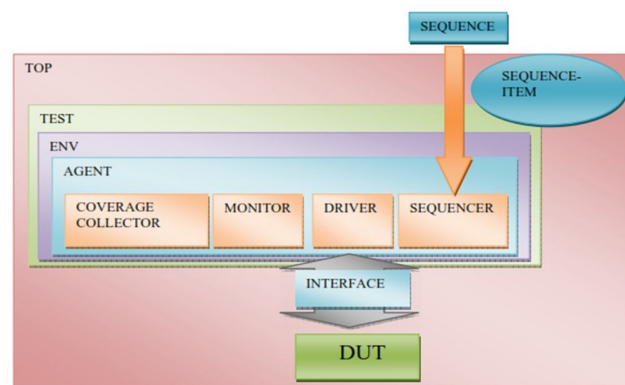


Fig.5. UVM Environment.

## V. CONCLUSION

The SystemVerilog verification environment produced alongside complete stream about verification need been examined. The Different classes for driver monitor, stimulus, environment and so on. Also modules alternately projects aggravated bring been aggregated is simulate and the outputs watched need aid demonstrated. Environment made totally wraps the DUT is utilitarian more assertion based coverage need been found. Assertion coverage found will be 100% and covergroup coverage may be discovered as 20.1%. The overall coverage may be discovered to make 100%. The SystemVerilog environment formed need been broadened should UVM toward calling the base class library also different confirmation segments. The UVM built nature's domain formed need been talked about for a little talk about UVM.

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